## ATTACHMENT A: SEARCH HISTORY

L Number	Hits	Search Text	DB	Time stamp
17	158	(test same device) and (trench same	USPAT;	2004/06/14
* '	100	capacitor) and DRAM	US-PGPUB;	11:09
		Capacitor, and Divin	EPO; JPO;	11.05
			DERWENT;	
			IBM TDB	
18	32	((test same device) and (trench same	USPAT;	2004/06/14
	52	capacitor) and DRAM) and (parallel same	US-PGPUB;	11:08
		capacitor() and blown, and (parallel same capacitor())	EPO; JPO;	11.00
		Capacitoryi	DERWENT;	
			IBM TDB	
19	5	(((test same device) and (trench same	USPAT;	2004/06/14
13	J	capacitor) and DRAM) and (parallel same	US-PGPUB;	11:08
		capacitor() and brain and (parallel same capacitor()) and (scribe same line)	EPO; JPO;	11.00
		capacito191// and (Scribe Same Time)	DERWENT;	
			IBM TDB	
20	29	((test same device) and (trench same	USPAT;	2004/06/14
20	29	capacitor) and DRAM) and (first same	US-PGPUB;	11:09
		transistor) and (second same transistor)	EPO; JPO;	11.09
		and (bit same contact)	DERWENT;	
		and (bit same contact)	IBM TDB	1
21	393	test and (trench same capacitor) and DRAM	USPAT;	2004/06/14
21	3,53	test and (trench same capacitor) and boom	US-PGPUB;	11:20
			EPO; JPO;	11.20
			DERWENT;	
			IBM TDB	i .
22	5	(test and (trench same capacitor) and	USPAT;	2004/06/14
22	Ĵ	DRAM) and ((((test same device) and	US-PGPUB;	11:21
	·	(trench same capacitor) and DRAM) and	EPO; JPO;	11,21
		(parallel same capacitor\$1)) and (scribe	DERWENT;	
		same line))	IBM TDB	
23	27		USPAT;	2004/06/14
20	2,	DRAM) and scribe	US-PGPUB;	11:22
		Jidii, did Jolist	EPO; JPO;	11.22
			DERWENT;	
			IBM TDB	
24	3	((test and (trench same capacitor) and	USPAT;	2004/06/14
		DRAM) and scribe) and 365/\$7.ccls.	US-PGPUB;	11:22
			EPO; JPO;	11.22
			DERWENT;	
			IBM TDB	
25	1	("6529427"   "2002/0142539"	USPAT	2004/06/14
		"2003/0003611").PN.		11:23
26	0	6693834.URPN.	USPAT	2004/06/14
				11:23
27	1	("6529427"   "2002/0142539"	USPAT	2004/06/14
	_	"2003/0003611").PN.	<b></b>	11:23